Thin Solid Films 589 (2015) 877

Contents lists available at ScienceDirect

Thin Solid Films

journal homepage: www.elsevier.com/locate/tsf

Corrigendum

Corrigendum to "Effect of thickness on structural and electrical properties of Al-doped ZnO films" [Thin Solid Films] 574 (2015) 162–168

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The authors apologize for some mistakes detected in the above-mentioned article. In the first place, the conductivity values of the vertical axis in Fig. 6 were wrong and, in fact, they differ from those mentioned in the discussion.

The amended Fig. 6 presents the plot with corrected conductivity values as a function of thickness for ZnO:Al films. As can be observed, conductivity increased almost linearly from 0.3 to 40 Ω^{-1} cm^{-1} for thicknesses ranging from 0.43 to 1.26 μm, respectively, and the conductivity of the thickest film (1.44 μm) decreased slightly.

Secondly, in the discussion describing this figure, the authors mentioned that the highest obtained conductivity was 50 Ω^{-1} cm^{-1}, while it should have been 40 Ω^{-1} cm^{-1}.

Finally, the authors should have concluded that the highest obtained value for conductivity was about 40 Ω^{-1} cm^{-1} rather than concluding that in all samples the conductivity was high and in the order of 50 Ω^{-1} cm^{-1}.

The authors would like to apologize for any inconvenience caused.

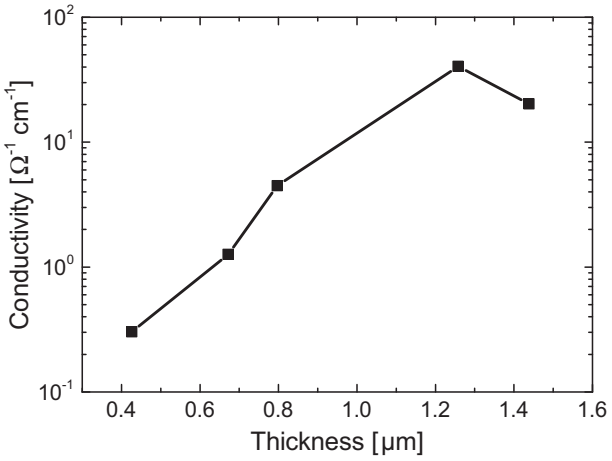

Fig. 6. Electrical conductivity of the Al-doped ZnO films as a function of film thickness. The solid line is only a guide to the eye.

DOI of original article: http://dx.doi.org/10.1016/j.tsf.2014.12.013.
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http://dx.doi.org/10.1016/j.tsf.2015.05.044